Abstracts

Enhanced Through-Reflect-Line Characterization of Two-Port Measuring Systems Using Free-Space Capacitance Calculation (Short Papers)

J.S. Kasten, M.B. Steer and R. Pomerleau. "Enhanced Through-Reflect-Line Characterization of Two-Port Measuring Systems Using Free-Space Capacitance Calculation (Short Papers)." 1990 Transactions on Microwave Theory and Techniques 38.2 (Feb. 1990 [T-MTT]): 215-217.

A through-reflect-line calibration procedure is presented wherein the free-space capacitance and propagation factor of the line standard are used to determine the line characteristic impedance. The method is applied to measurement of a microstrip via.

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